## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| Serial No.: | 10/644,116                            | ) | Conf. No.: | 6516 |
|-------------|---------------------------------------|---|------------|------|
| Filed:      | August 20, 2003                       | ) |            |      |
| Title:      | Whole-Wafer<br>Photoemission Analysis | ) |            |      |
| Inventors:  | Jeffrey Blackwood et al.              | ) |            |      |
| Art Unit:   | 2624                                  | ) |            |      |
| Examiner:   | Daniel G. Mariam                      | ) |            |      |
| Atty. Ref:  | 03-0515                               | ) |            |      |

## **RESPONSE TO THE OFFICE ACTION MAILED NOVEMBER 6, 2006**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed November 6, 2006, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application. A Petition for Extension of Time is enclosed, extending the deadline for responding to the Office Action to March 6, 2007.

Therefore, this Response is considered timely.